


<b>Search Notes</b> 	<b>Application/Control No.</b> 10577896	<b>Applicant(s)/Patent Under Reexamination</b> HACK ET AL.
	<b>Examiner</b> ALEXANDER C WITKOWSKI	<b>Art Unit</b> 2853

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Stephen D. Meier, Supervisory Patent Examiner.	09/21/2008	ACW
Limited classification search: 347/ 47	09/21/2008	ACW
Text search; see search history.	09/21/2008	ACW

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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